

Substitute Form PTO-1449 (Modified) DEC 06 2002 37 CFR 1.98(b)	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 05542-459003	Application No. 09/134,147
	Information Disclosure Statement by Applicant (Use several sheets if necessary)			
	Applicant Wallace T.Y. Tang		Filing Date August 14, 1998	Group Art Unit 1763

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>sm</i>	AA	4,272,924	06/16/81	Masuko et al.			
<i>sm</i>	AB	4,328,068	05/04/82	Curtis			
<i>sm</i>	AC	4,436,367	03/1984	Lewis et al.			
<i>sm</i>	AD	4,529,986	07/1985	d'Auria et al.			
<i>sm</i>	AE	4,569,717	02/1986	Ohgami et al.			
<i>sm</i>	AF	4,618,262	10/1986	Maydan et al.			
<i>sm</i>	AG	4,672,200	06/1987	Claypool et al.			
<i>sm</i>	AH	4,711,516	12/1987	Graber			
<i>sm</i>	AI	4,776,695	10/1988	Van Pham et al.			
<i>sm</i>	AJ	4,793,895	12/1988	Kaanta et al.			
<i>sm</i>	AK	4,879,258	11/1989	Fisher			
<i>sm</i>	AL	4,929,828	05/1990	Claypool			
<i>sm</i>	AM	4,948,259	08/14/90	Enke et al.			
<i>sm</i>	AN	4,998,021	03/1991	Mimasaka			
<i>sm</i>	AO	4,999,509	03/1991	Wada et al.			
<i>sm</i>	AP	5,020,283	06/04/91	Tuttle			
<i>sm</i>	AQ	5,036,015	07/1991	Sandhu et al.			
<i>sm</i>	AR	5,046,849	09/1991	Severin et al.			
<i>sm</i>	AS	5,069,002	12/1991	Sandhu et al.			
<i>sm</i>	AT	5,081,421	01/1992	Miller et al.			
<i>sm</i>	AU	5,081,796	01/1992	Schultz			
<i>sm</i>	AV	5,097,430	03/17/92	Birang			
<i>sm</i>	AW	5,120,966	06/1992	Kondo			
<i>sm</i>	AX	5,132,617	07/21/92	Leach et al.			
<i>sm</i>	AY	5,196,353	03/23/93	Sandhu et al.			
<i>sm</i>	AZ	5,219,787	06/15/93	Carey et al.			
<i>sm</i>	AAA	5,234,868	08/10/93	Cote			

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Examiner Signature <i>SR MacAlta</i>	Date Considered 1/30/03
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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U.S. Patent Documents

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hyn	ABB	5,242,524	09/07/93	Leach et al.			
hyn	ACC	5,257,478	11/02/93	Hyde et al.			
hyn	ADD	5,265,378	11/30/93	Rostoker			
hyn	AEE	5,294,289	03/15/94	Heinz et al.			
hyn	AFF	5,297,364	03/29/94	Tuttle			
hyn	AGG	5,308,438	05/03/94	Cote et al.			
hyn	AHH	5,308,447	05/1994	Lewis et al.			
hyn	AII	5,321,304	06/14/94	Rostoker			
hyn	AJJ	5,329,734	07/19/94	Yu			
hyn	AKK	5,332,467	07/26/94	Sune et al.			
hyn	ALL	5,337,015	08/09/94	Lustig et al.			
hyn	AMM	5,394,655	03/07/95	Allen et al.			
hyn	ANN	5,413,651	05/09/95	Otruba			
hyn	AOO	5,413,941	05/09/95	Koos et al.			
hyn	APP	5,433,651	07/1995	Lustig et al.			
hyn	AQQ	5,483,568	01/1996	Yano et al.			
hyn	ARR	5,499,733	03/1996	Litvak			
hyn	ASS	5,605,760	02/25/97	Roberts			
hyn	ATT	5,893,796	04/13/99	Birang et al.			
hyn	AUU	5,910,043	06/08/99	Manzonic et al.			
hyn	AVV	5,948,259	09/07/99	Deguitre et al.			
hyn	AWW	5,964,643	10/12/99	Birang et al.			
hyn	AXX	6,045,439	04/04/00	Birang et al.			
hyn	AYY	6,280,290	08/28/01	Birang et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No

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							Yes	No
<i>JS</i>	AZZ	✓625,573	08/15/61	Canada				
<i>JS</i>	AAAA	✓0 352 740 A2	01/31/90	EPO				
<i>JS</i>	ABBB	✓0 738 561 A1	03/28/96	EPO				
<i>JS</i>	ACCC	✓1,075,634	10/19/54	France			Yes	
<i>JS</i>	ADDD	✓57-138575	08/26/82	Japan			Abstr.	
<i>JS</i>	AEEE	✓58-4353	01/11/83	Japan			Abstr.	
<i>JS</i>	AFFF	59-57215	04/1984	Japan				
<i>JS</i>	AGGG	✓59-74635	04/27/84	Japan			Abstr.	
<i>JS</i>	AHHH	✓61-164773	07/25/86	Japan			Abstr.	
<i>JS</i>	AIII	✓2-222533	09/05/90	Japan			Abstr.	
<i>JS</i>	AJJJ	✓3-234467	10/18/91	Japan			Yes	
<i>JS</i>	AKKK	✓5-138531	06/01/93	Japan			Abstr.	
<i>JS</i>	ALLL	✓5-309558	11/22/93	Japan			Yes	
<i>JS</i>	AMMM	✓7-52032	02/28/95	Japan			Yes	
<i>JS</i>	ANNN	✓WO 93/20976	10/28/93	WIPO				

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
<i>JS</i>	AOOO	✓Anonymous, "End-Point Detection of Oxide Polishing and Planarization of Semiconductor Devices," <u>Research Disclosure</u> , 1992, No. 340, Kenneth Mason Publications Ltd., England
<i>JS</i>	APPP	✓Carotta et al., "Effect of thickness and surface treatment on silicon wafer reflectance," <u>Solar Energy Materials and Solar Cells</u> , 1992, 27:265-272
<i>JS</i>	AQQQ	✓Henck, "In situ real-time ellipsometry for film thickness measurement and control," <u>J. Vac. Sci. Technol. A.</u> , 1992, 10(4):934-938
<i>JS</i>	ARRR	✓Jurczyk et al., "Process Detection System," IBM Technical Disclosure Bulletin, 1975, 18(6):1867-1870
<i>JS</i>	ASSS	✓Nakamura et al., "Mirror Polishing of Silicon Wafers (4 th Report)," - Development of Bowl Feed and Double Side Polishing Machine with In-situ Thickness Monitoring of Silicon Wafers, <u>JSPE</u> , pp. 129-134
<i>JS</i>	ATTT	✓Sautter et al., "Development process control and optimization utilizing an end point monitor," <u>SPIE</u> , 1989, 1087:312-316

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